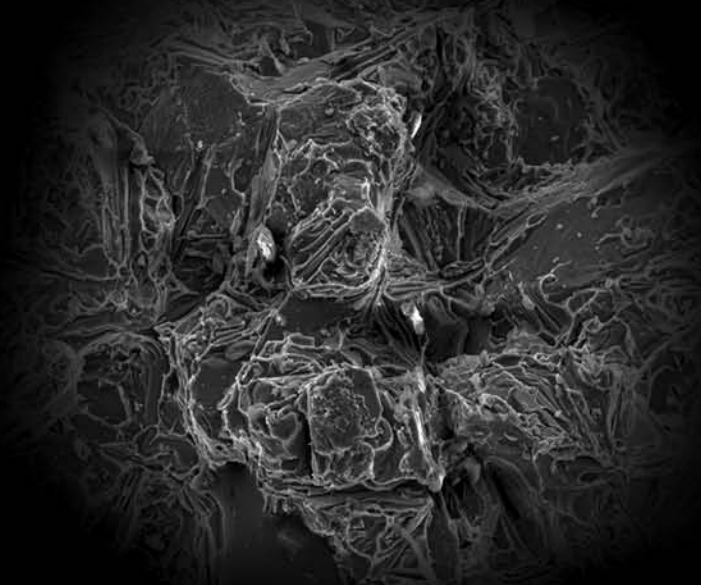


JEOL Application Driven Solutions for Material Sciences

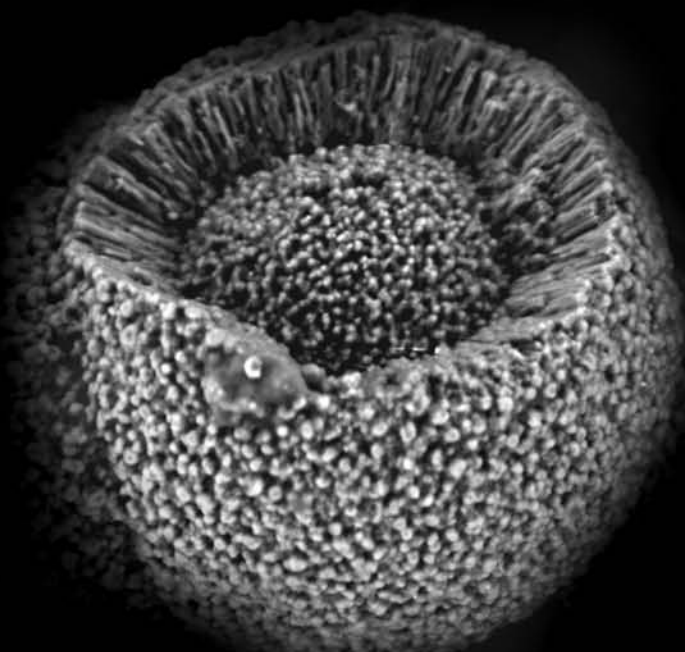


Jet Turbine

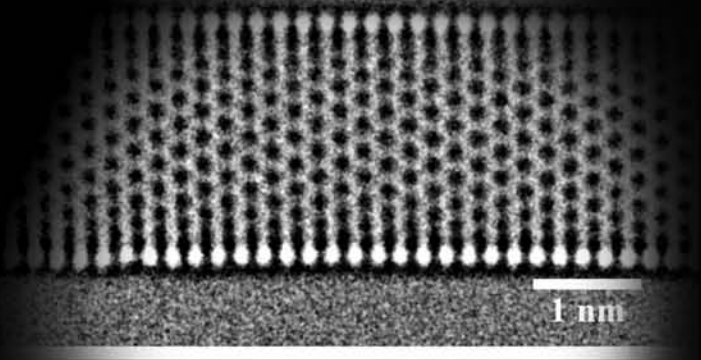


Ductile fracture taken on JSM-6610LV

Bring your samples to one of our European
Application Centres and see for yourself



Spray Coating taken on JSM-7600F



1 nm

From subatomic imaging through to large
sample failure analysis; JEOL instruments
lead the way in Materials development

Carbon Nanotube, taken on a double
corrected 2200FS at 80KV

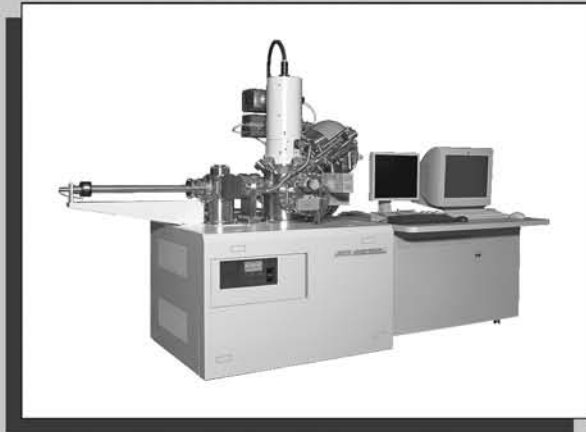
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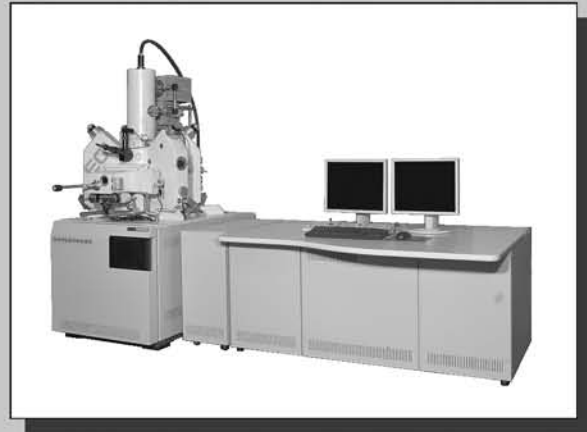
Spray coating, courtesy of SIFCO
Ductile fracture taken for an episode of BBC's Waking the Dead
Carbon Nanotube, courtesy of Jamie Warner, Neil Young and Angus Kirkland, Oxford University

JEOL's High-Performance Products From Surface Analysis to Nano Order



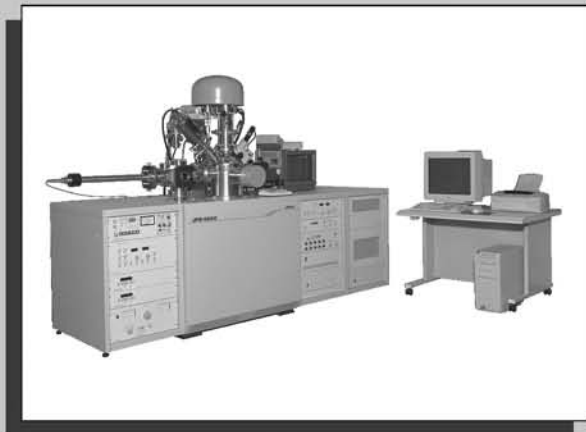
JAMP-9500F
Field Emission Auger Microprobe

We introduce the JAMP-9500F Field Emission Auger Microprobe (Scanning Auger Microscope), featuring the world's highest spatial resolution. The JAMP-9500F is an ideal instrument for nanoarea analysis with a high spatial resolution almost the same as the diameter of the primary electron beam.



JXA-8500F
Field Emission Electron Probe Microanalyzer

JEOL developed JXA-8500F Field Emission Electron Probe Microanalyzer with a newly-developed thermal field emission gun. JXA-8500F enables submicron analysis, which was difficult with conventional EPMA.



JPS-9200
Photoelectron Spectrometer

Versatile measurement from high-spatial resolution XPS analysis (30 μm) to macro-area XPS imaging (50 \times 18 mm^2), thus meeting the needs of the nanotechnology era. Newly designed input lens system, combining a magnetic-field lens and electrostatic-field lens, achieves high-sensitivity measurement.



JSPM-5400
Scanning Probe Microscope

JSPM-5400 performs high quality, various data measurement with many automated features making it easy to use for both novice and expert users.

- EWithout damages, high-resolution observations can beget using Non-contact mode AFM.
- EUnder high vacuum, cool or heated, stable observations are possible.



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